United States Patent [19]

Brickwood

[11] **Des. 254,655**

[45] ** **Apr. 8, 1980**

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[54] **MICROMETER**

[75] Inventor: **David Brickwood**, London, England

[73] Assignee: **James Neill Holdings Limited,**
Sheffield, England

[**] Term: **14 Years**

[21] Appl. No.: **829,988**

[22] Filed: **Sep. 1, 1977**

[51] **Int. Cl.** .... **D10—04**
[52] **U.S. Cl.** **D10/73**
[58] **Field of Search** D10/70–74,
D10/73; 33/143 M, 143 J, 143 R, 143 K, 143 F

[56] **References Cited**

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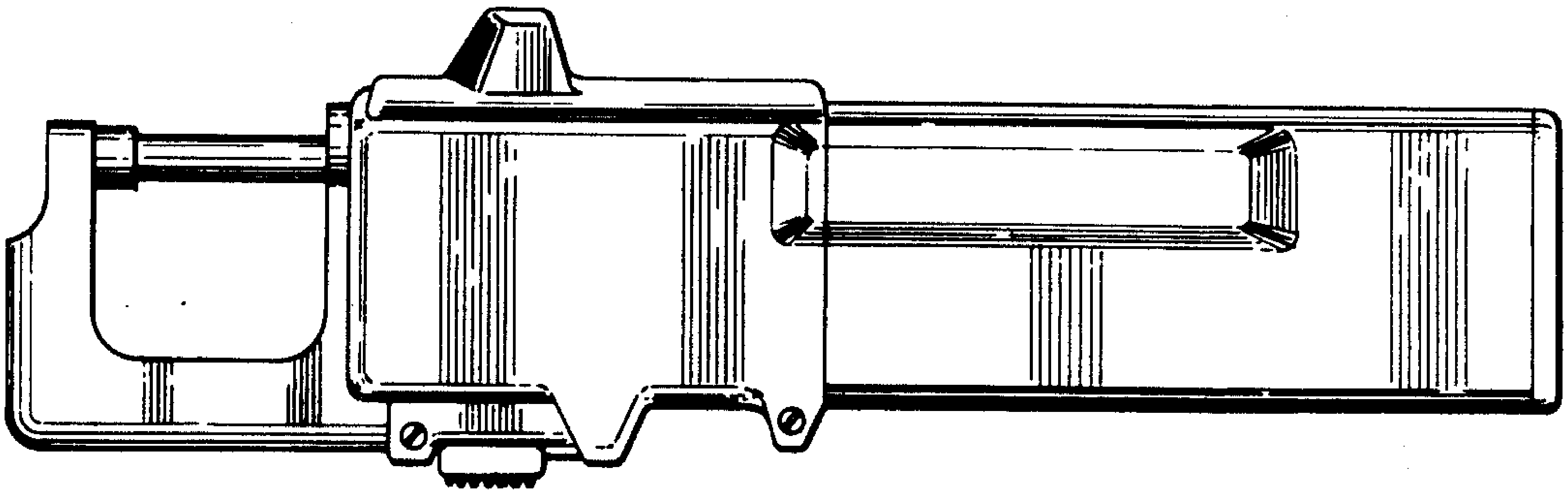
Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Robert A. Cesari

[57] **CLAIM**

The ornamental design for a micrometer, substantially as shown.

DESCRIPTION

FIG. **1** is a front elevational view of a micrometer showing my new design;
FIG. **2** is a rear elevational view thereof;
FIG. **3** is a right side elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a bottom plan view thereof;
FIG. **6** is a top plan view thereof.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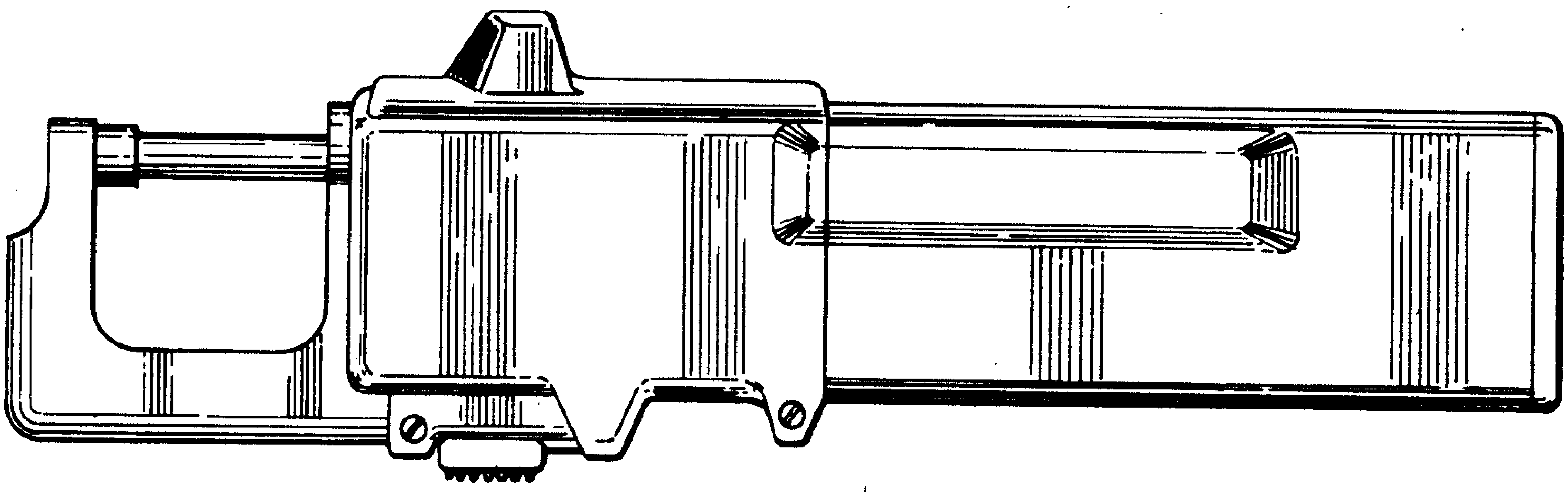

FIG. 1

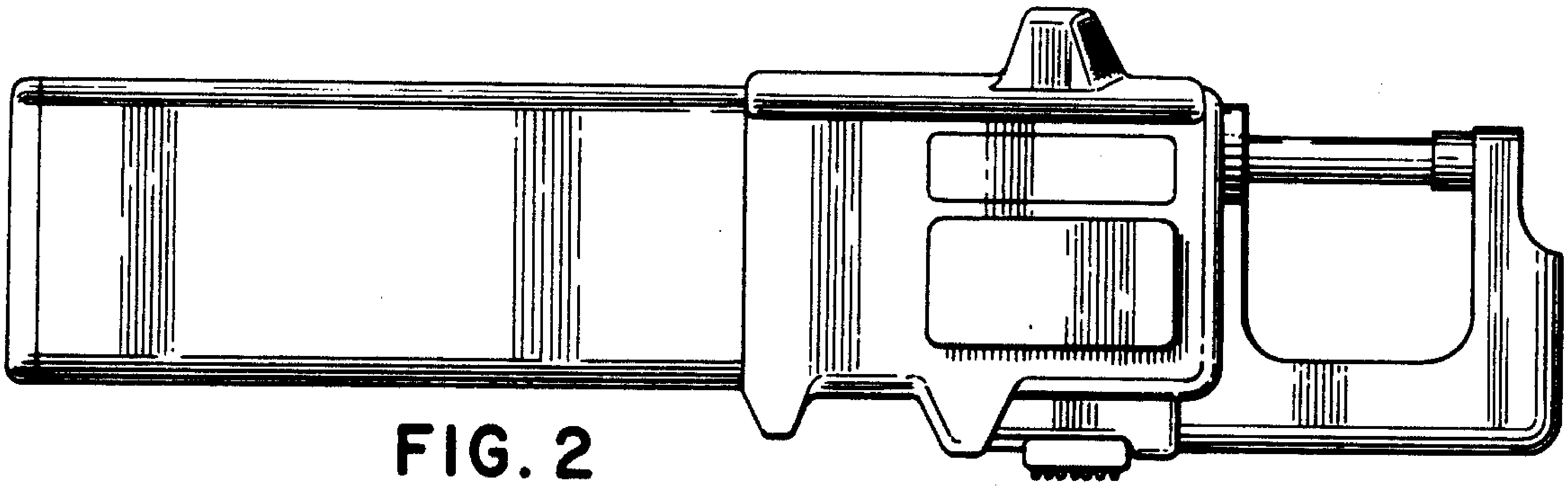

FIG. 2

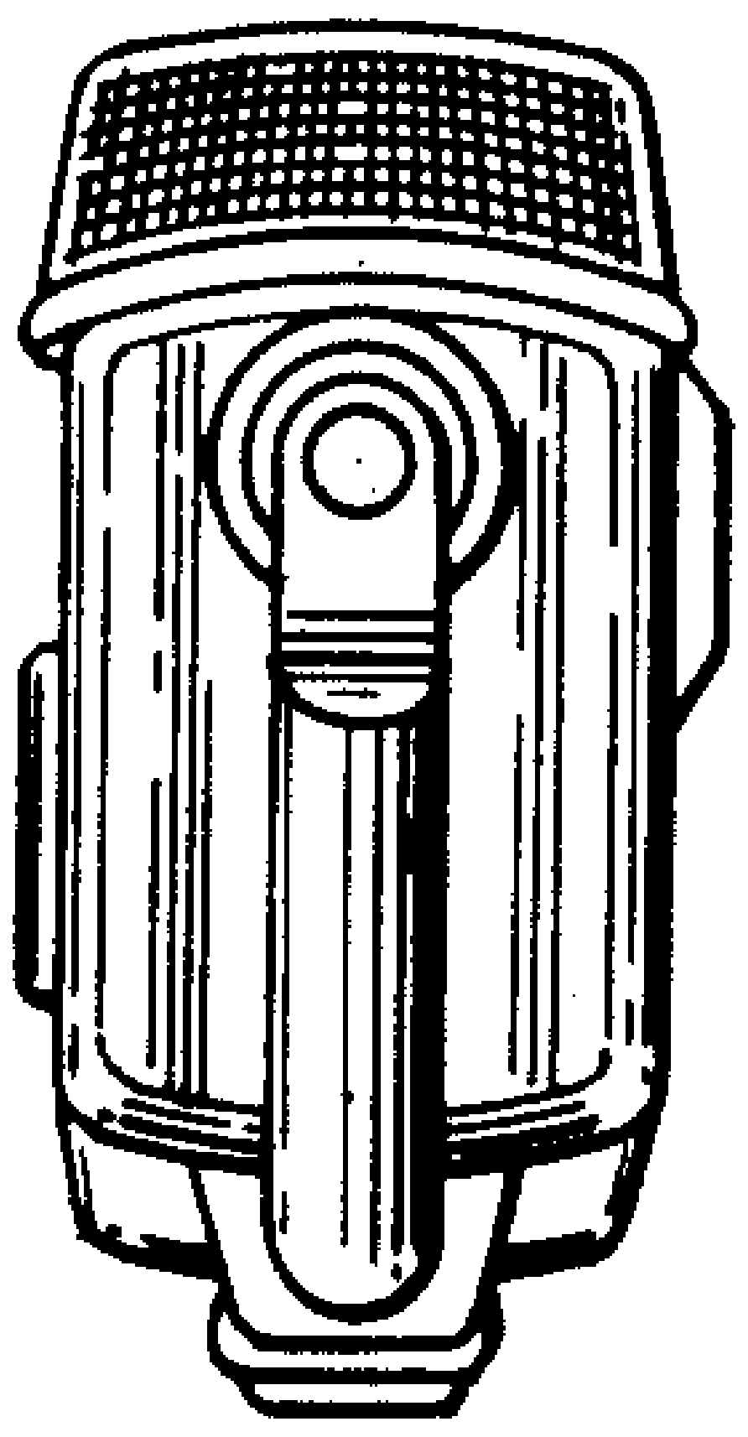

FIG. 3

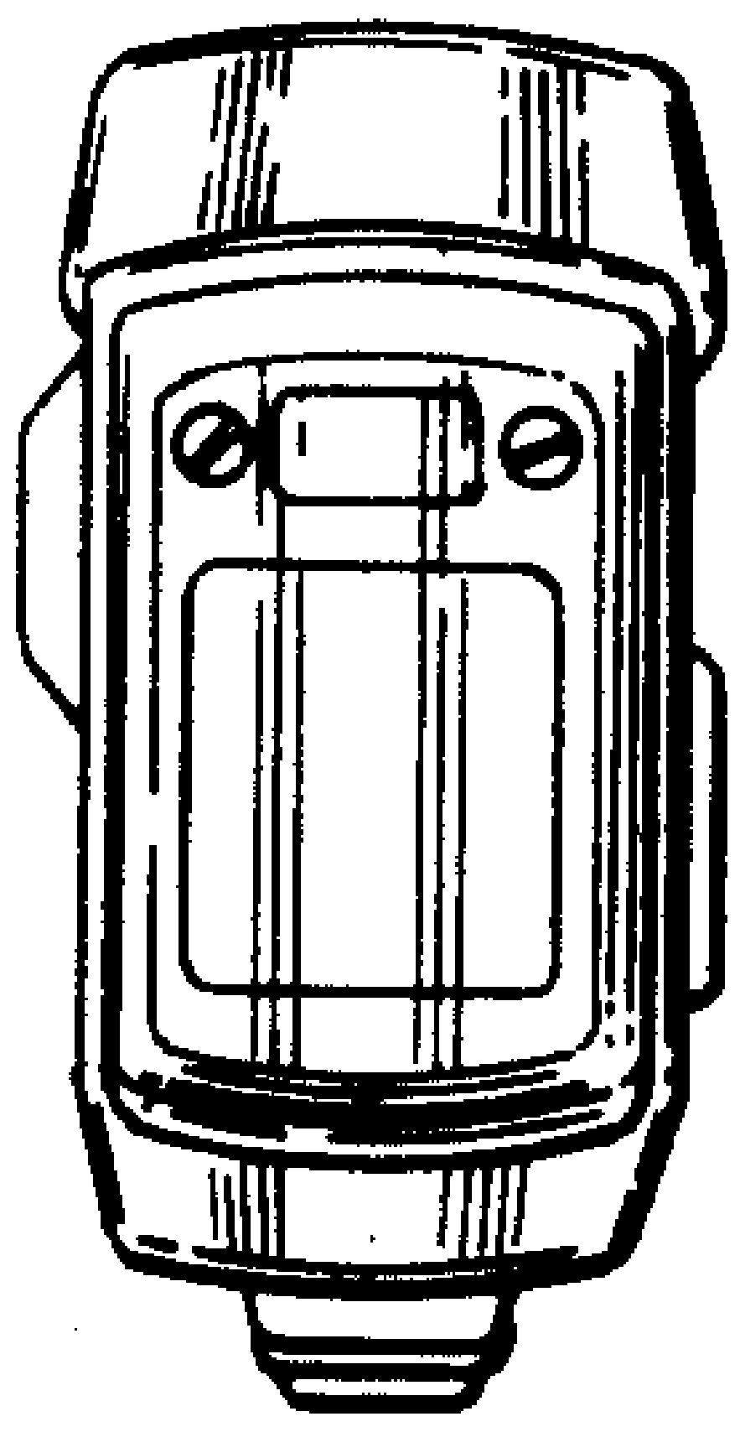

FIG. 4

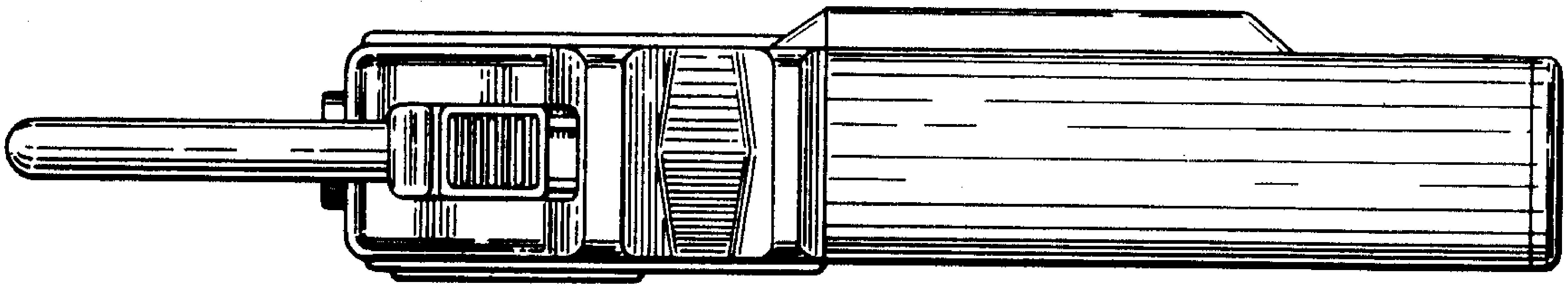

FIG. 5

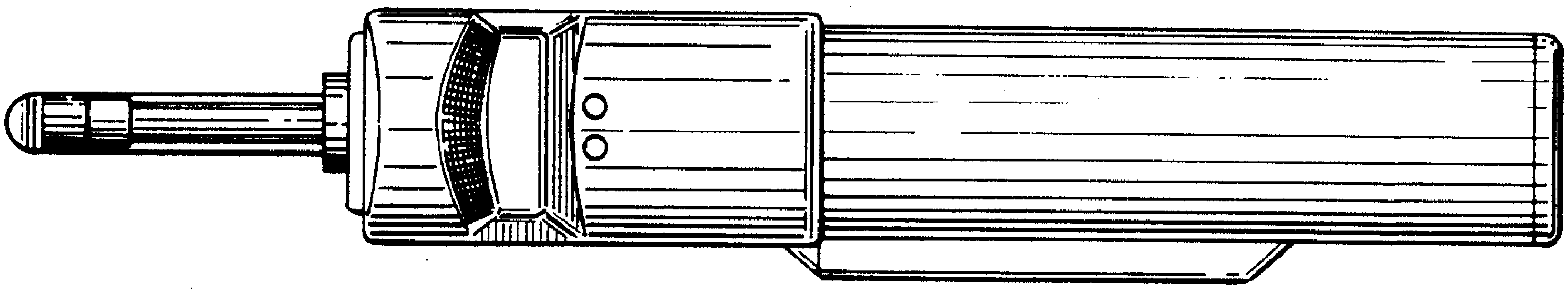

FIG. 6